

Welcome



DIN Workshop on Image
Technology 2005

Stefan Jäger 19.4.05



Multispectral CIELAB camera for the evaluation of automobile color coatings

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PhD scholarship financed by Volkswagen AG

Agenda

- Motivation
- Project Objectives
- Challenges
- System Overview
- Colorimetric and Spectral Accuracy
- Summary and Outlook

Motivation

- **Improve color accuracy and the aesthetic appearance**
The quality of the surface is a crucial part for the overall quality impression of an industrial product like an automobile
- **Reduce quality costs**
Quality costs are a notable part of the production expenses. In the production process costs for sorting and rectification arise. Quality problems discovered at the consumer will occur as costs for warranty and annulment. Additionally the loss of confidence and credibility should not be neglected
- **Need for process control with 100% sample size**
No current color measurement system for the automobile industry offers automated spectral multi-angle color measurement for our needs

Improve surface quality while reducing quality costs

Motivation

Example of mismatching colors

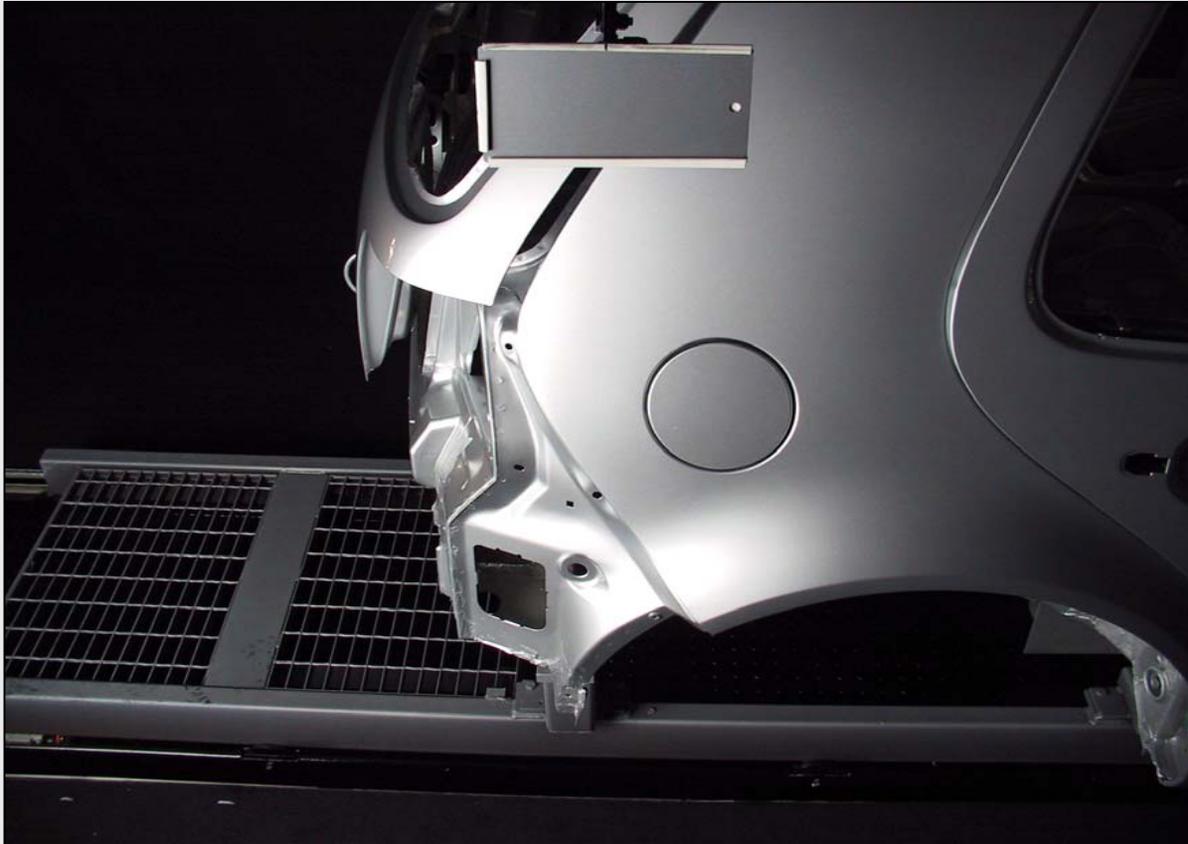
Rear Bumper in „reflex silver“ too light compared to car body



Motivation

Example of mismatching colors (2)

Fuel flap in „reflex silver“ too dark



Project Objectives

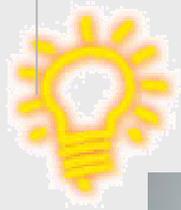
- **Design of a spectral color measurement system**
Intended for a process control with a sample size close to 100%
- **Measurement and evaluation of a sample as a whole**
Realizing a high spacial resolution in comparison to commonly used color measurement equipment in the automobile industry, namely the X-Rite MA68II. Evaluate areas of interest, i.e. connection zone of attachment part and car body
- **Matching attachment parts and car bodies early**
Decide at an early stage, even before shipping from the supplier to the assembly line, if the parts comply with the specifications of the customer
- **Gaining knowledge and experience**
Generally in the field of spectral imaging in industrial environments. In addition the production process monitored can be understood more thoroughly

Challenges

- **Samples are not plane surfaces**
Evaluating curved and bended objects like bumpers and rear-mirror casings
- **Effect colors are observer-illumination angle dependent**
Metallics and pearls have to be measured with multiple geometries
(15° , 25° , 45° , 75° , 110°)
- **Constraints of production process must be considered**
Integration in production line, time constraints for imaging and calculation
- **Reconstruction of spectra is not trivial**
Algorithms have to be adopted and adapted to the specific needs of the project

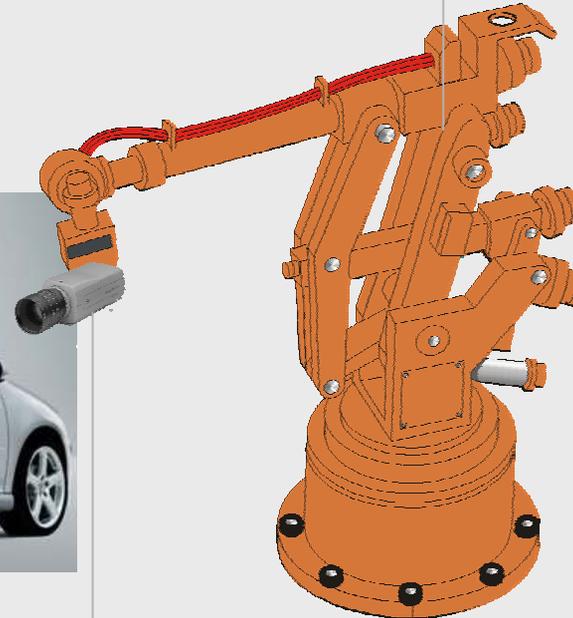
System Overview – Measurement Station

Scene Illumination



Positioning System

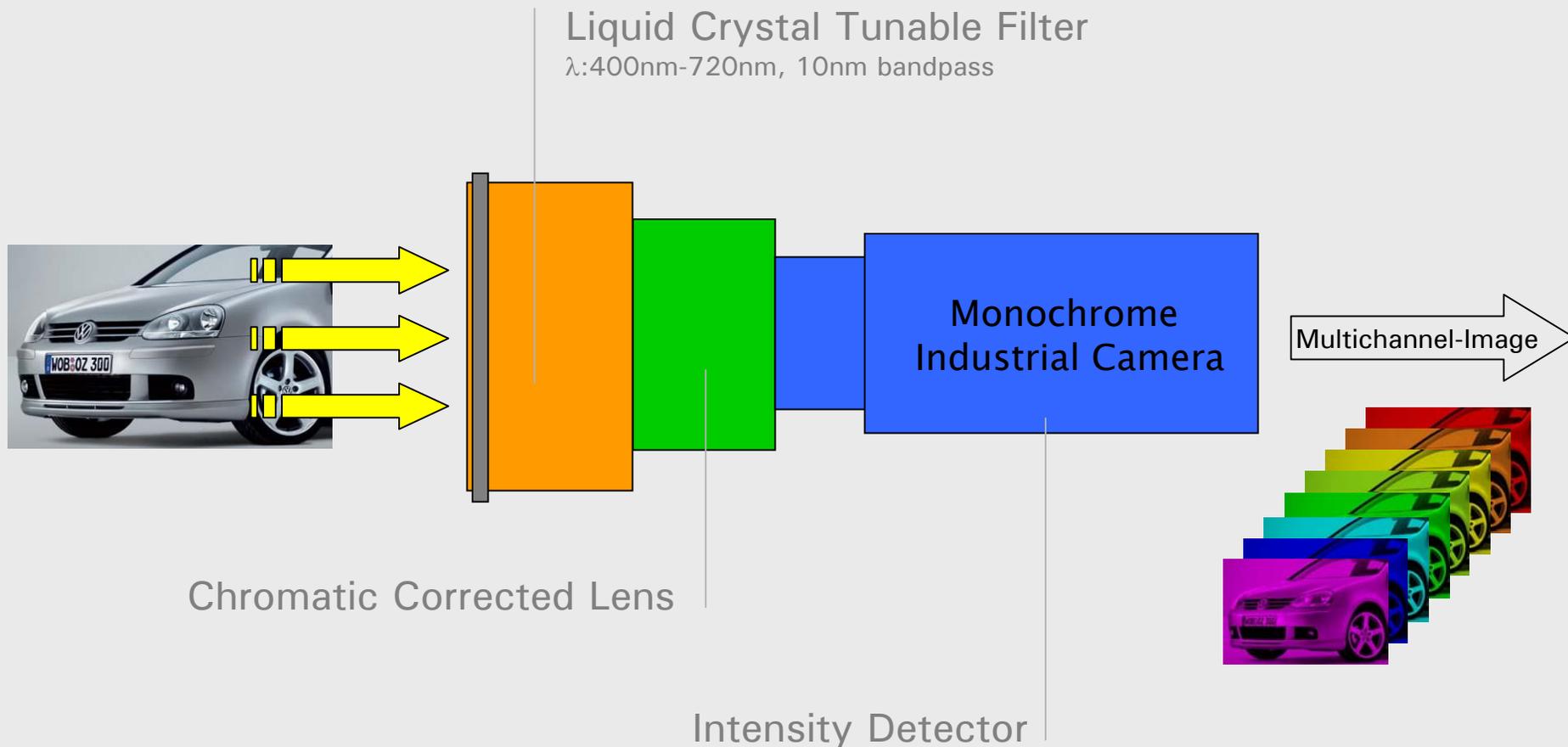
Sample Scene



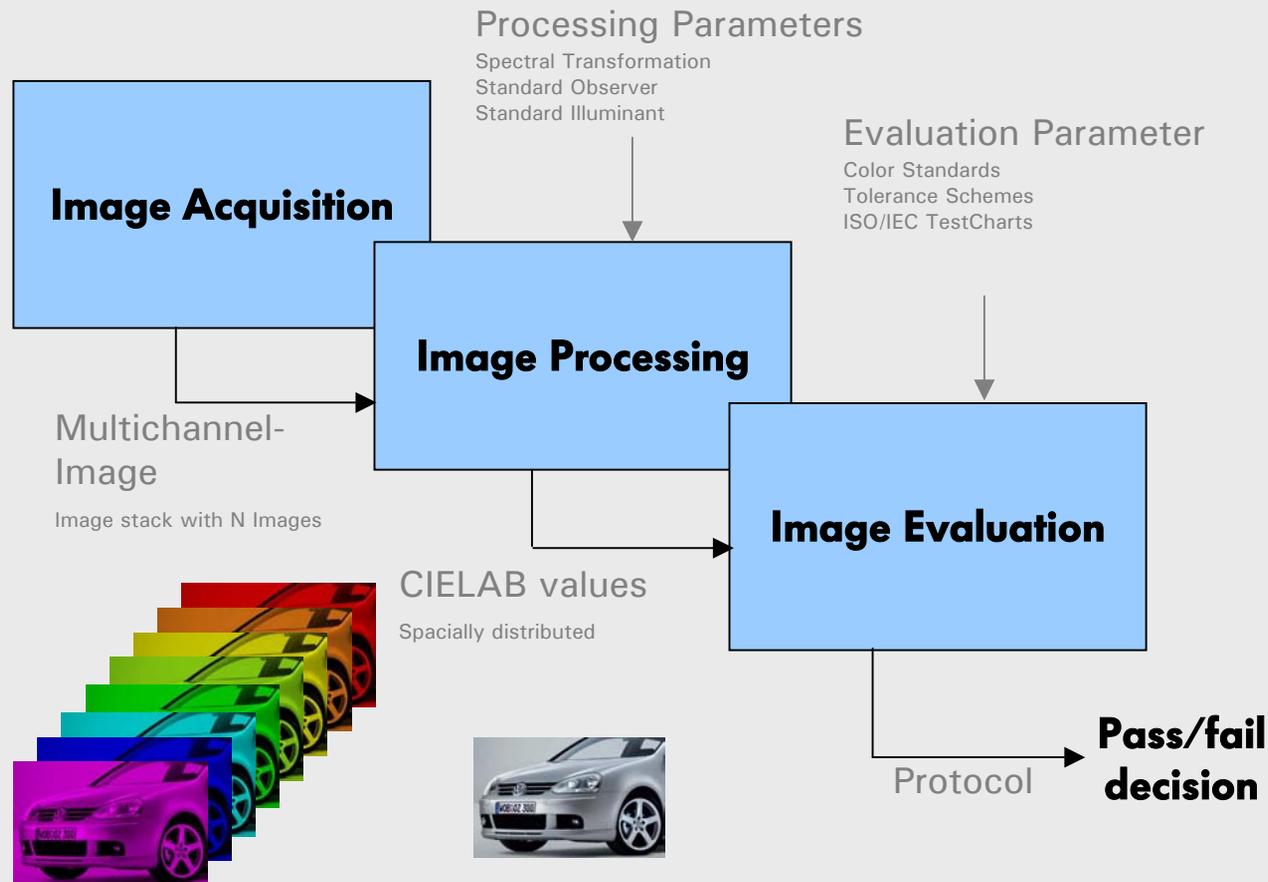
Spectral Measuring Device

System Software

System Overview – Spectral Measuring Device



System Overview – Measurement Process



System Overview – Transformation Determination



Reference System:
Set of reflectances
(*reflectance vectors of patches*)

Correlation of data



Multispectral Measuring Device:
Set of camera responses
(*intensity vectors of patches*)

Transformation

Reconstruct reflectance vectors from
camera response vectors

System Accuracy – Evaluation Approach

- **Select error metrics**

- Spectral: Root Mean Square of differences at spectral sample points
- Colorimetric: CIE's dE Formula with different illuminants (10° Observer)

- **Select verification set of colors**

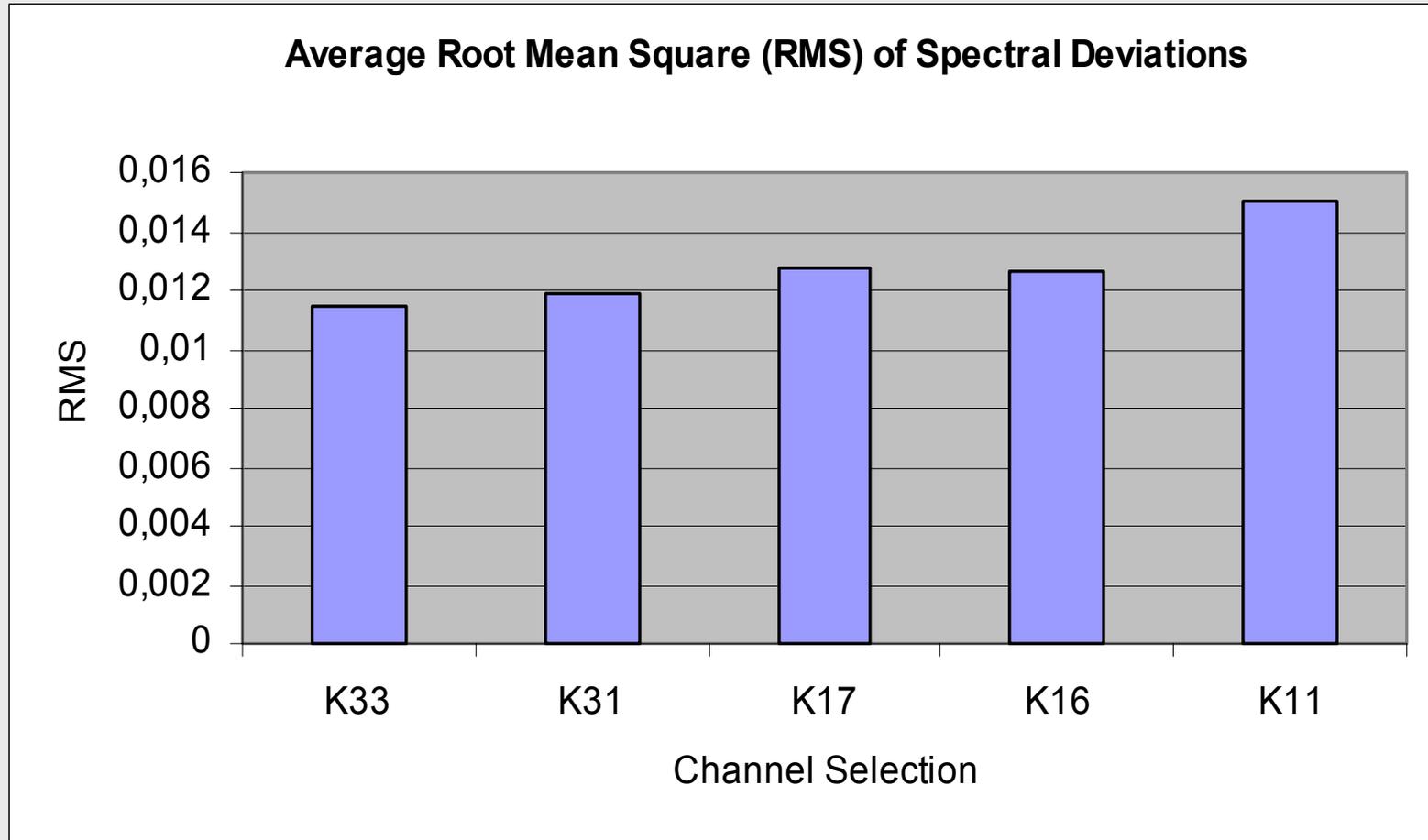
Colors are spectrally imaged and compared with data from a reference spectral measuring device (380nm-730nm)

- **Define channel sets for acquisition**

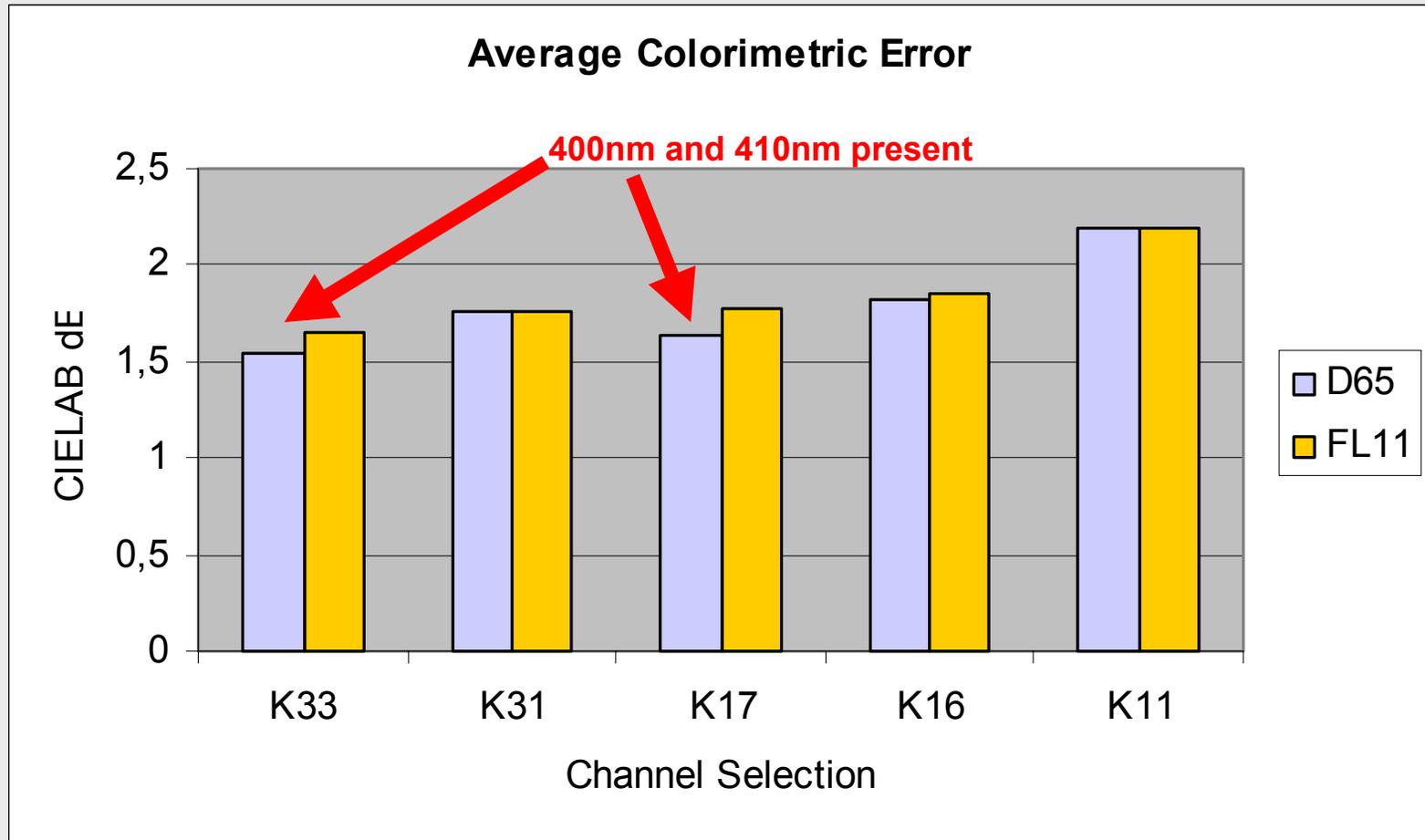
Reduction of acquisition and processing time. Short wavelenghts need extensive exposure time.

- K33: 400-720nm 10nm steps
- K31: 420-720nm 10nm steps
- K17: 400-720nm 20nm steps
- K16: 420-720nm 20nm steps
- K11: 420-720nm 30nm steps

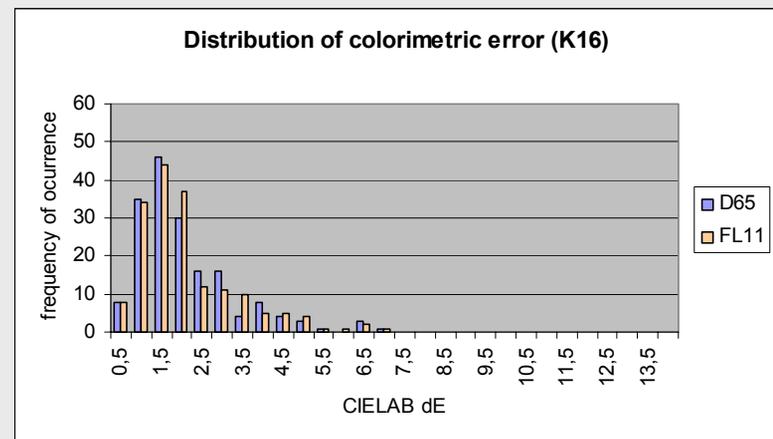
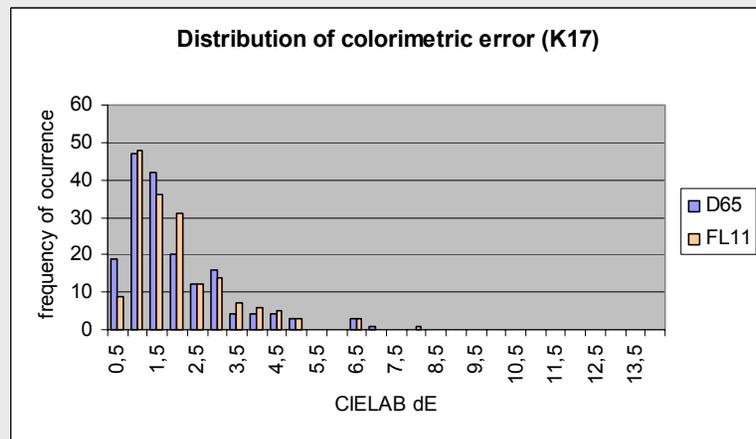
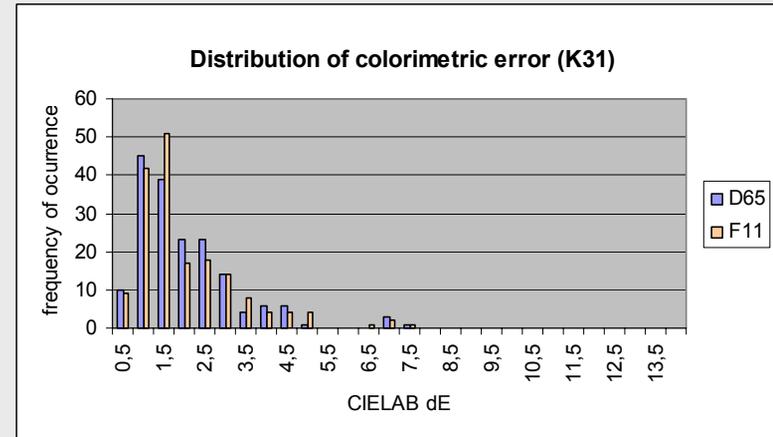
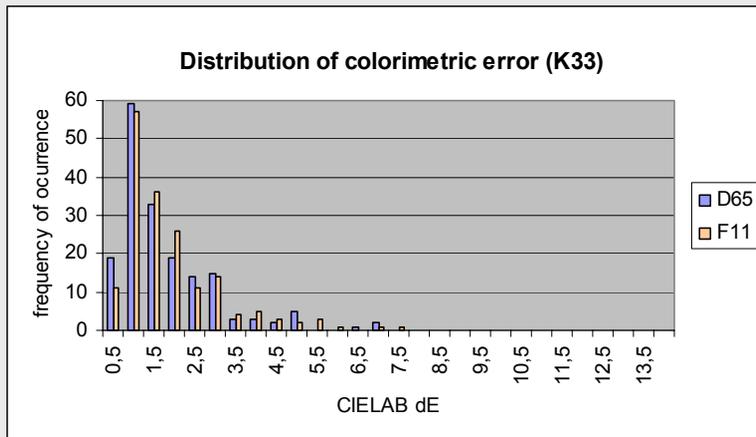
System Accuracy – Spectral Results



System Accuracy – Colorimetric Results



System Accuracy – Colorimetric Results



Summary and Outlook

- **Weak correlation of spectral and colorimetric error**
Non-linear behavior of observer sensitivity and spectral distribution of sample illumination
- **Improvement potentials for spectral reconstruction**
Different options for reconstruction, use of optimized equipment (e.g. pellettier cooled camera, improved filter, improved lens system)
- **Improvement of colorimetric accuracy**
Additional step for colorimetric regression can be introduced

Promising approach for absolute color measurement as well as for color measurement relative to a defined physical standard

Thank you....

Discussion
and
Questions



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